

Search Notes

Application/Control No.

10/511,791

Examiner

John E. Chapman

Applicant(s)/Patent under
Reexamination

AKIYAMA ET AL.

Art Unit

2856

SEARCHED

Class	Subclass	Date	Examiner
73	598 600 620 644	9/24/2007	JC
209	590	9/24/2007	JC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR